S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/810,320	STOCK ET AL.
Examiner	Art Unit
Anthony Weier	1761

	SEAR	CHED	
Class	Subclass	Date	Examiner
426	614, 601	6/6/2007	AW

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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DATE 6/6/2007	AW
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